



Vishay Siliconix

N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A)	Q _g (Typ.)		
30	$0.068 \text{ at V}_{GS} = 4.5 \text{ V}$	3.6 ^a	3 nC		
	0.085 at V _{GS} = 2.5 V	3.4	3110		

TO-236 (SOT-23) G 1 3 D Top View Si2300DS (P2)*

* Marking Code

Ordering Information: Si2300DS-T1-GE3 (Lead (Pb)-free and Halogen-free)

FEATURES

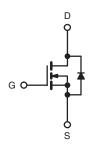
- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET® Power MOSFET
- 100 % R_g Tested
- Compliant to RoHS Directive 2002/95/EC



ROHS COMPLIANT HALOGEN FREE

APPLICATIONS

- DC/DC Converter for Portable Devices
- · Load Switch



N-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	30	V	
Gate-Source Voltage		V _{GS}	± 12	V	
	T _C = 25 °C		3.6 ^a		
Continuous Drain Current (T _{.I} = 150 °C)	T _C = 70 °C		3.0		
Continuous Diain Current (1, = 150 C)	T _A = 25 °C	I _D	3.1 ^{b, c}		
	T _A = 70 °C	1	2.5 ^{b, c}	Α	
Pulsed Drain Current		I _{DM}	15		
Continuous Source-Drain Diode Current	T _C = 25 °C		1.4		
	T _A = 25 °C	l _s	0.9 ^{b, c}		
Maximum Power Dissipation	T _C = 25 °C		1.7		
	T _C = 70 °C		1.1	10/	
	T _A = 25 °C	P _D	1.1 ^{b, c}	W	
	T _A = 70 °C	1	0.7 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C	
Soldering Recommendations (Peak Temperature) ^{d, e}			260	°C	

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{b, d}	t ≤ 5 s	R _{thJA}	90	115	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	$R_{th,IF}$	60	75	0/11		

Notes:

- a. Package limited
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 5 s.
- d. Maximum under steady state conditions is 130 °C/W.

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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static						•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V, I}_{D} = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		21		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	I _D = 250 μA		- 3.2			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	0.6		1.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 12 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	μА	
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	10			Α	
Drain-Source On-State Resistance ^a		$V_{GS} = 4.5 \text{ V}, I_D = 2.9 \text{ A}$		0.055	0.068	Ω	
	R _{DS(on)}	$V_{GS} = 2.5 \text{ V}, I_D = 2.6 \text{ A}$		0.070	0.085		
Forward Transconductance ^a	9 _{fs}	$V_{DS} = 15 \text{ V}, I_D = 2.9 \text{ A}$		13		S	
Dynamic ^b						1	
Input Capacitance	C _{iss}			320		pF	
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		45			
Reverse Transfer Capacitance	C _{rss}			19			
Total Gate Charge	Qg	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 3.1 \text{ A}$		6.5	10	nC	
				3	4.5		
Gate-Source Charge	Q_{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 3.1 \text{ A}$		0.8			
Gate-Drain Charge	Q_{gd}			0.5			
Gate Resistance	R_{g}	f = 1 MHz	0.6	3.2	6.4	Ω	
Turn-On Delay Time	t _{d(on)}			10	15	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 6 Ω		15	25		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong$ 2.5 A, V_{GEN} = 4.5 V, R_g = 1 Ω		20	30		
Fall Time	t _f			11	20		
Turn-On Delay Time	t _{d(on)}			5	10		
Rise Time	t _r	V_{DD} = 15 V, R_L = 6 Ω		12	20		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong$ 2.5 A, V_{GEN} = 10 V, R_g = 1 Ω		15	25		
Fall Time	t _f			10	15		
Drain-Source Body Diode Characteristi	cs						
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			1.4	А	
Pulse Diode Forward Current	I _{SM}				15		
Body Diode Voltage	V _{SD}	$I_S = 2.5 \text{ A}, V_{GS} = 0 \text{ V}$		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			11	20	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 2.5 A, dl/dt = 100 A/μs, T _J = 25 °C		5	10	nC	
Reverse Recovery Fall Time	t _a	1 _F = 2.5 Λ, αι/αι = 100 Α/μs, 1 _J = 25 °C		7		ne	
Reverse Recovery Rise Time	t _b	t _b		4		ns	

Notes:

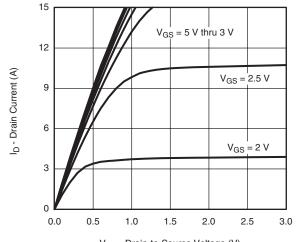
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

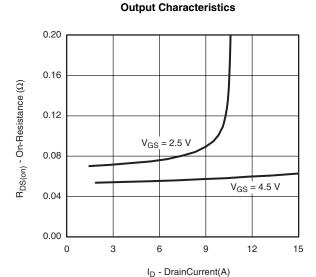


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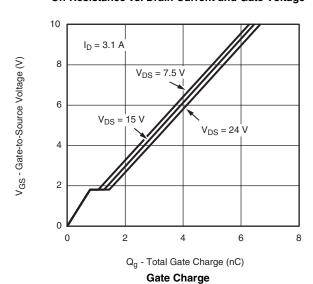
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



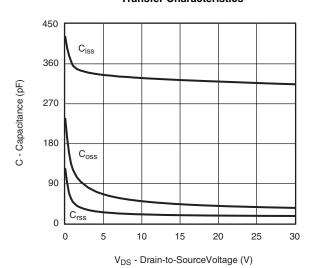
V_{DS} - Drain-to-Source Voltage (V)



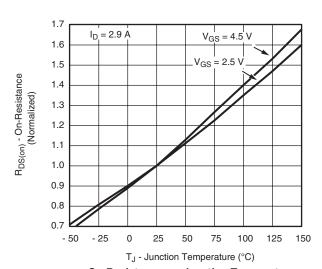
On-Resistance vs. Drain Current and Gate Voltage



V_{GS} - Gate-to-Source Voltage (V) **Transfer Characteristics**



Capacitance

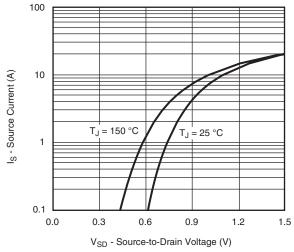


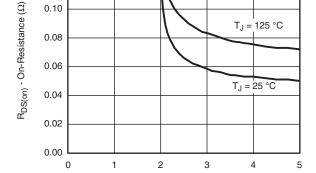
On-Resistance vs. Junction Temperature

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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted





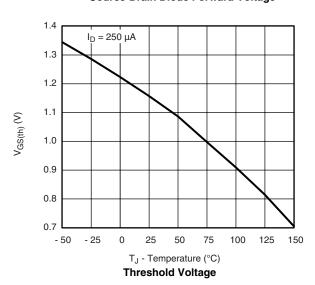
 $I_D = 2.9 \text{ A}$

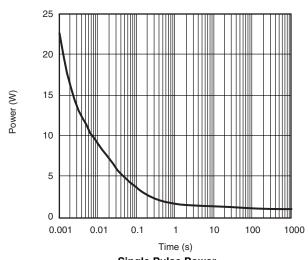
0.12

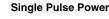
Source-Drain Diode Forward Voltage

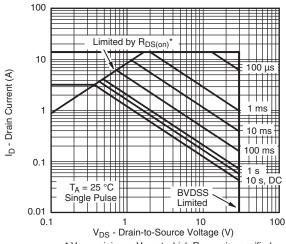
V_{GS} - Gate-to-Source Voltage (V)

On-Resistance vs. Gate-to-Source Voltage









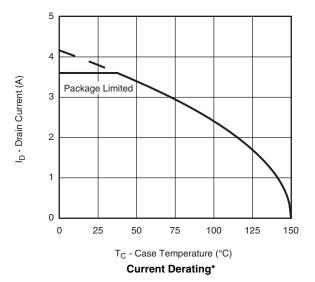
* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

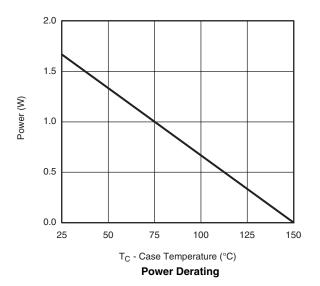
Safe Operating Area, Junction-to-Ambient



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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



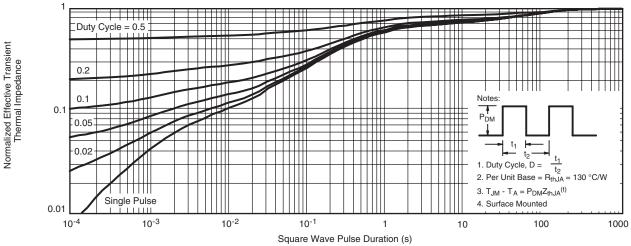


^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

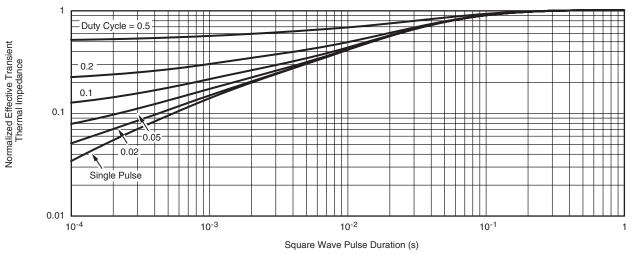
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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot

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